Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/813,025	YUAN, TI-WEN	
Examiner	Art Unit	
Nhan T. Le	2618	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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